

AMENDMENT TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims

1. (Original) A transistor comprising:
a stack comprising:
a silicon on insulator layer having a plurality of channels;
a silicon oxide insulation layer adjacent the silicon on insulator layer; and
a dielectric layer adjacent the silicon oxide insulation layer; and
a gate electrode,
wherein the gate electrode covers a portion of the stack;
wherein at least one channel has a gate configuration that is different than the remaining channels.
2. (Original) The transistor according to claim 1, wherein the at least one channel has a first thickness that is greater than the thickness of the remaining channels.
3. (Original) The transistor according to claim 1, wherein the at least one channel has a different gate dielectric than the remaining channels.
4. (Original) The transistor according to claim 3, wherein the gate dielectric of the at least one channel is a high-k dielectric, and the gate dielectric of the remaining channels is a material selected from the group comprising silicon dioxide, nitride oxide, and a silicon oxide that has undergone a plasma nitridation process.
5. (Original) The transistor according to claim 1, wherein the stack further comprises a protection layer located between the dielectric layer and the gate electrode.
6. (Original) The transistor according to claim 5, wherein the protection layer is a metal.

7. (Original) The transistor according to claim 5, wherein the protection layer is a thin polysilicon.

8. (Original) The transistor according to claim 1, wherein the dielectric layer is a high-k dielectric material.

9. (Original) The transistor according to claim 1, wherein the stack and the gate electrode are incorporated into a finFET device.

10. (Original) A transistor comprising:
a stack comprising:
a silicon on insulator layer;
a silicon oxide insulation layer on the silicon on insulator layer;
a dielectric layer on the silicon oxide insulation layer, wherein the dielectric layer is a high-k dielectric material; and
a protection layer on the dielectric layer; and
a gate electrode covering a portion of the stack.

11. (Original) The transistor according to claim 10, wherein the protection layer is a metal.

12. (Original) The transistor according to claim 10, wherein the protection layer is a polysilicon.

13. (Original) The transistor according to claim 10, wherein the stack and the gate electrode are incorporated into a finFET device.

14. (Withdrawn) A method for providing a transistor comprising the steps of:
providing a silicon on insulator layer;

providing a silicon oxide insulation layer;
providing a dielectric layer;
removing at least a portion of the silicon oxide insulation layer and the dielectric layer to
form a gate stack; and
forming a gate electrode,
wherein the gate electrode covers a portion of the gate stack.

15. (Withdrawn) The method according to claim 14, wherein the stack further
comprises a protection layer on the dielectric layer.

16. (Withdrawn) The method according to claim 15, wherein the protection layer is
a metal.

17. (Withdrawn) The method according to claim 15, wherein the protection layer is
a polysilicon.

18. (Withdrawn) The method according to claim 14, wherein the dielectric layer is a
high-k dielectric material.

19. (Withdrawn) The method according to claim 14, wherein the gate stack and the
gate electrode are incorporated into a finFET device.

20. (Withdrawn) The method according to claim 14, wherein the step of removing
further comprises: providing a resist layer on a portion of the dielectric layer; and etching the
silicon oxide insulation layer and the dielectric layer to remove at least a portion of the silicon
oxide insulation layer and the dielectric layer.